

Features

- Higher System Efficiency
- Reduced Cooling Requirements
- 175°C operating temperature
- Increased Power Density
- Increased System Switching Frequency

Key Parameters

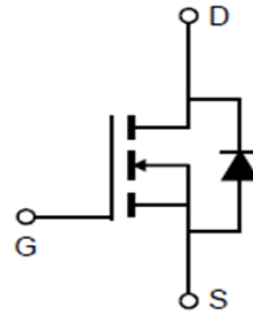
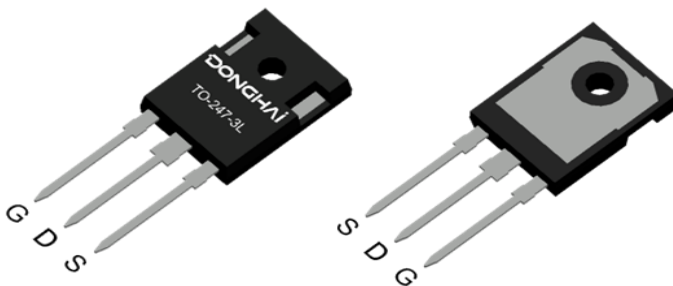
V_{DS}	1200V
$R_{DS(on)typ}$	16mΩ
I_D	110A
V_{th}	2.5V

Applications

- Solar and UPS inverters
- Power Supplies
- High Voltage DC/DC Converters
- Switch Mode Power Supplies
- Pulsed Power applications



TO-247-3



Marking & Packing Information

Part #	Package	Marking	Tube/Reel	Qty(pcs)
DCC016M120G3	TO-247-4	DCC016M120G3	Tube	240/box

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage (V _{GS} =0V, I _D =100μA)	V _{DS}	1200	V
Gate-Source voltage	V _{GSmax}	-8/+22	V
Recommend Gate-Source Voltage	V _{GSop}	-4/+18	V
Continuous drain current (V _{GS} =18V) TC = 25°C TC = 25°C(Package limit) TC = 100°C	I _D	110 160 78	A
Pulsed drain current (T _C = 25°C, t _p limited by T _{jmax})	I _{D pulse}	314	A
Power dissipation (T _C = 25°C)	P _{tot}	556	W
Operating junction and storage temperature	T _j , T _{stg}	-55~+175	°C

Thermal Resistance

Parameter	Symbol	typ	Unit
Thermal resistance, junction – case	R _{thJC}	0.27	°C/W
Thermal resistance, junction – ambient(min. footprint)	R _{thJA}	34	

Electrical Characteristic (at T_j = 25 °C, unless otherwise specified)

Static Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Drain-source breakdown voltage	BV _{DSS}	1200	-	-	V	V _{GS} =0V, I _D =100μA
Gate threshold voltage	V _{GS(th)}	2.0	2.5	3.0	V	V _{DS} =V _{GS} , I _D =20mA T _j =25°C T _j =175°C
Zero gate voltage drain current	I _{DSS}	-	-	100	μA	V _{DS} =1200V, V _{GS} =0V T _j =25°C T _j =175°C
Gate-source leakage current	I _{GSS}	-	-	250	nA	V _{GS} =-8/22V, V _{DS} =0V
Drain-source on-state resistance	R _{DS(on)}	-	16	21	mΩ	V _{GS} =18V, I _D =50A T _j =25°C T _j =175°C
Transconductance	g _{fs}	-	16.3	-	S	V _{DS} =20V, I _D =50A T _j =25°C T _j =175°C

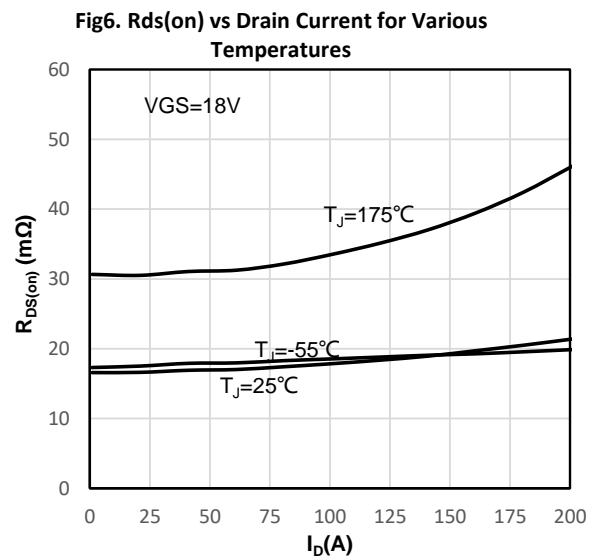
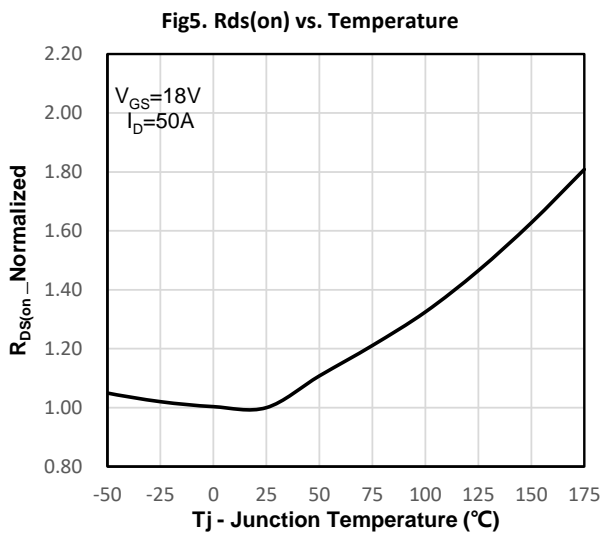
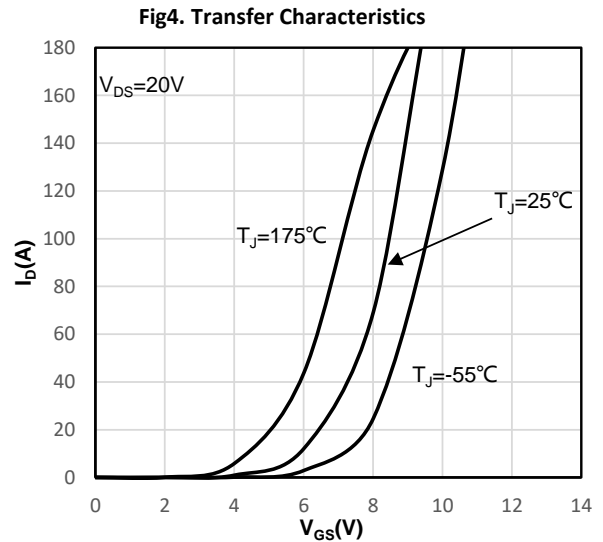
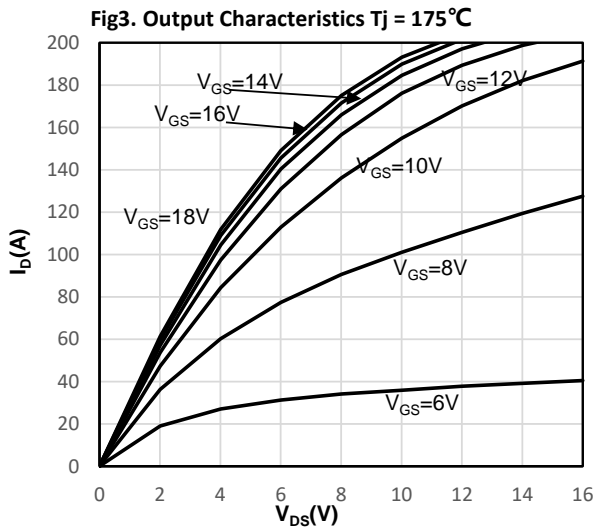
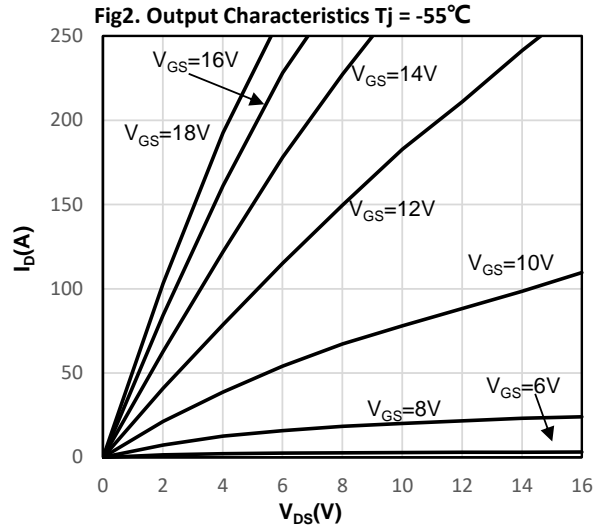
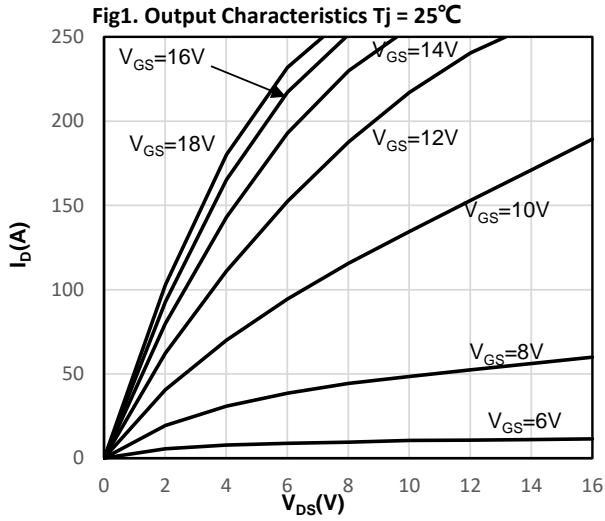
Dynamic Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Input Capacitance	C_{iss}	-	3064	-	pF	$V_{GS}=0V, V_{DS}=1000V,$ $f=1MHz$
Output Capacitance	C_{oss}	-	180	-		
Reverse Transfer Capacitance	C_{rss}	-	16.8	-		
Gate Total Charge	Q_G	-	158	-	nC	$V_{GS}=-4/18V,$ $V_{DS}=800V, I_D=50A,$ $f=1MHz$
Gate-Source charge	Q_{gs}	-	37	-		
Gate-Drain charge	Q_{gd}	-	34	-		
Turn-on delay time	$t_{d(on)}$	-	32	-	ns	$V_{DS}=800V,$ $V_{GS}=-4V/18V,$ $I_D=50A,$ $R_{G(ext)}=2.5\Omega,$ $L=100\mu H$
Rise time	t_r	-	36	-		
Turn-off delay time	$t_{d(off)}$	-	53	-		
Fall time	t_f	-	15	-		
Internal Gate Resistance	$R_{G(int)}$	-	3.4	-	Ω	$f=1MHz, V_{AC}=25mV$
Turn-On Switching Energy	E_{ON}	-	1415	-	μJ	$V_{DS}=800V,$ $V_{GS}=-4V/18V,$ $I_D=50A,$ $R_{G(ext)}=2.5\Omega,$ $L=100\mu H$
Turn-Off Switching Energy	E_{OFF}	-	478	-		

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Diode Max Current	I_S	-	-	110	A	-
Diode Forward Voltage	V_{SD}	-	3.4	-	V	$V_{GS}=-4V, I_{SD}=25A$ $T_j=25^\circ C$
		-	3.0	-		$T_j=175^\circ C$
Diode Reverse Recovery Time	t_{rr}	-	21.7	-	ns	$VR=800V, I_{SD}=50A,$ $dI/dt=1000A/\mu s$
Diode Reverse Recovery Charge	Q_{rr}	-	170	-	nC	
Peak Reverse Recovery Current	I_{rrm}	-	13	-	A	

Typical Characteristics Diagram



Typical Characteristics Diagram

Fig7. Rds(on) vs Temperature for Various Gate Voltage

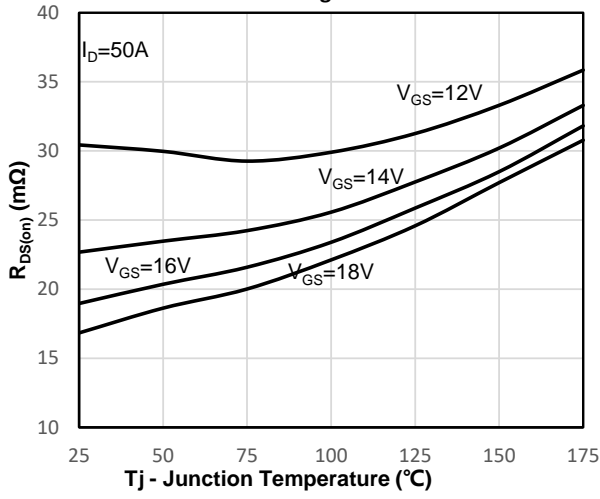


Fig8. Capacitance Characteristics

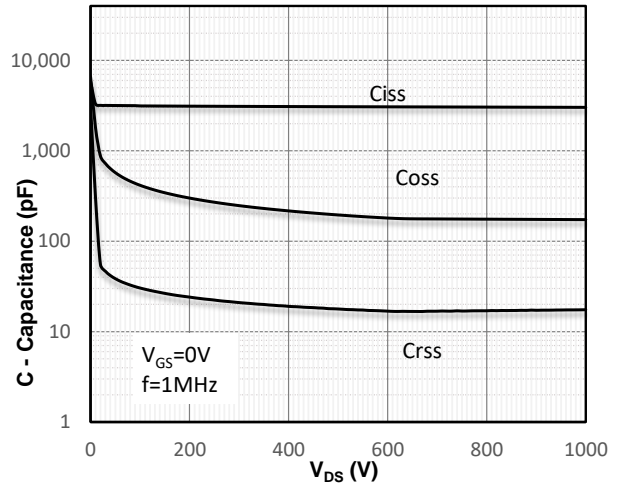


Fig9. Gate Charge Characteristics

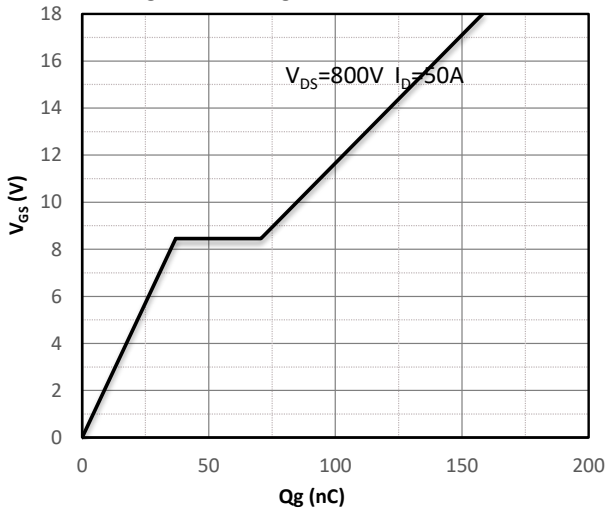


Fig10. Threshold Voltage- Junction Temperature Curve

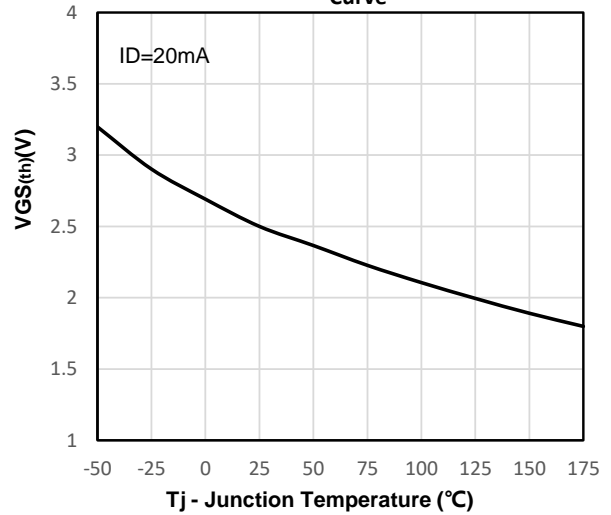


Fig11. Body Diode Characteristic at 25°C

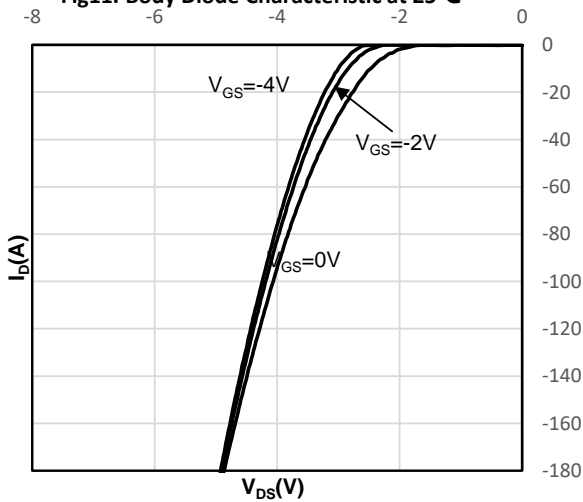
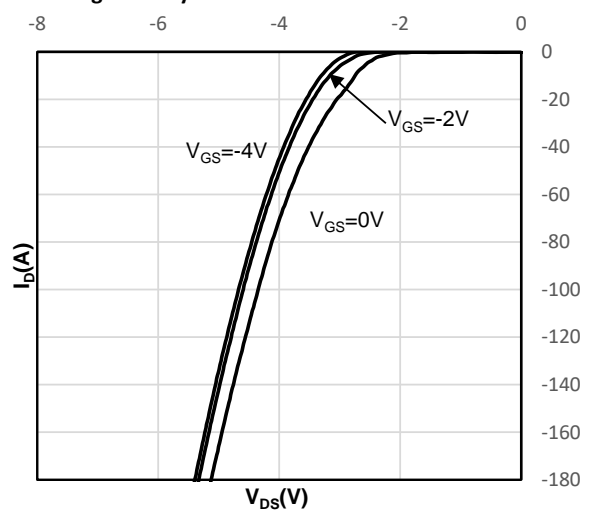
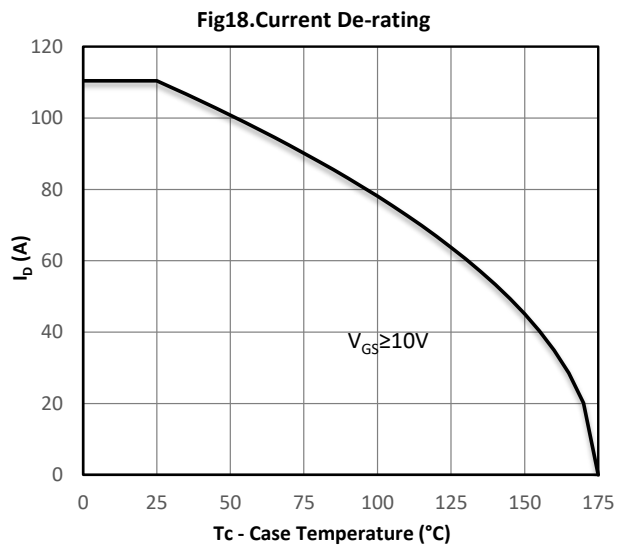
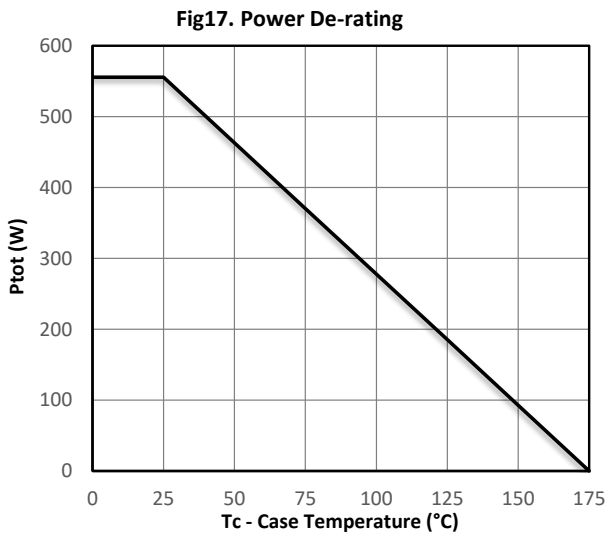
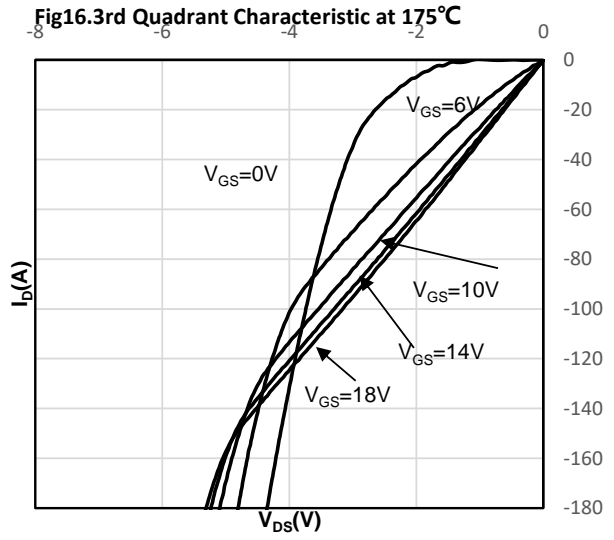
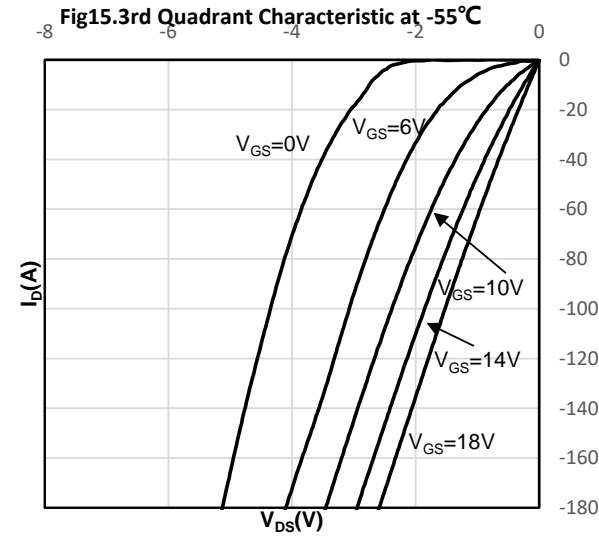
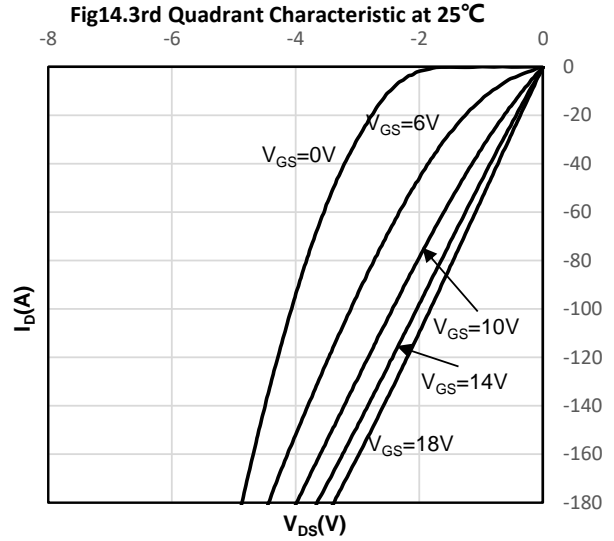
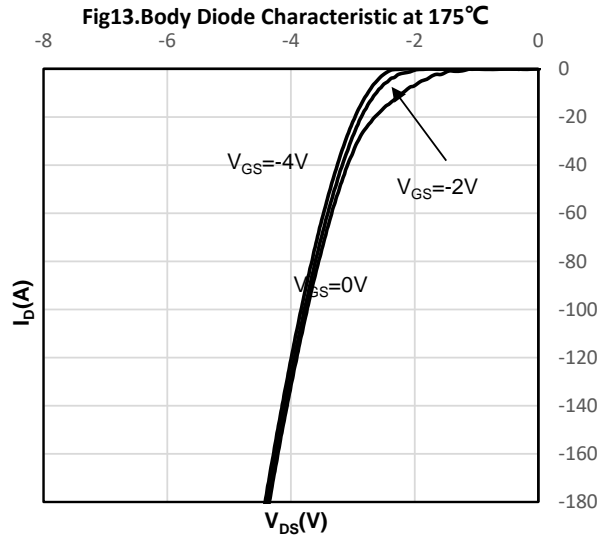


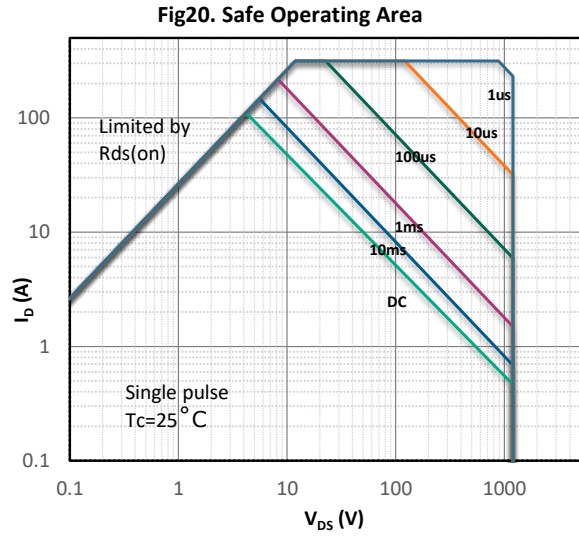
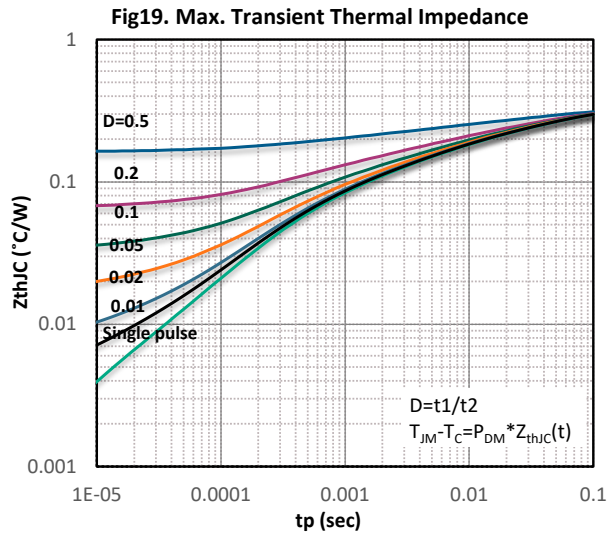
Fig12. Body Diode Characteristic at -55°C



Typical Characteristics Diagram

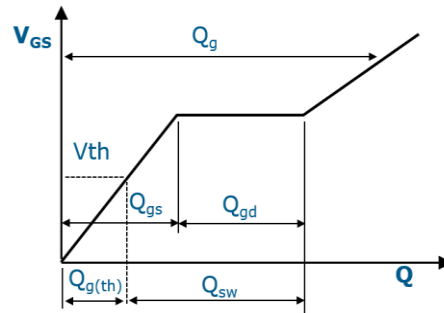
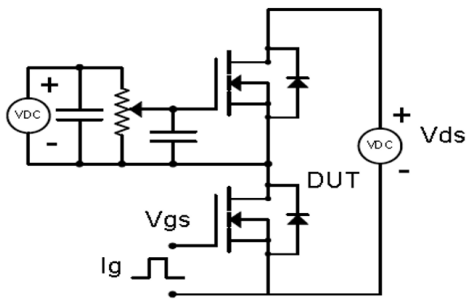


Typical Characteristics Diagram

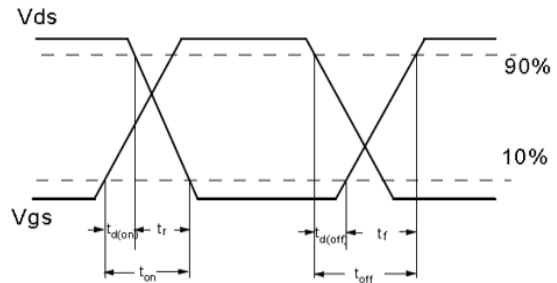
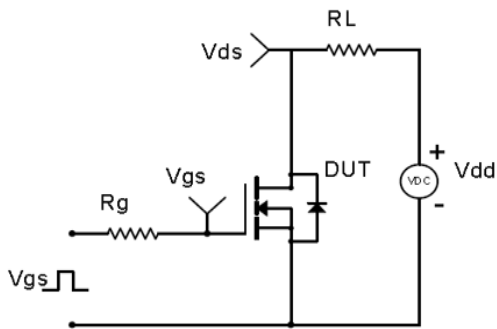


Test Circuit & Waveform

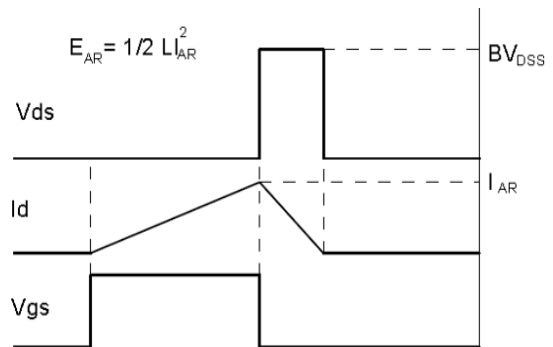
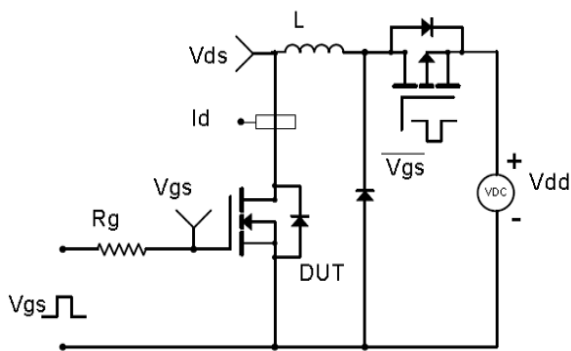
Gate Charge Test Circuit & Waveform



MOSFET Switching Test Circuit & Waveform

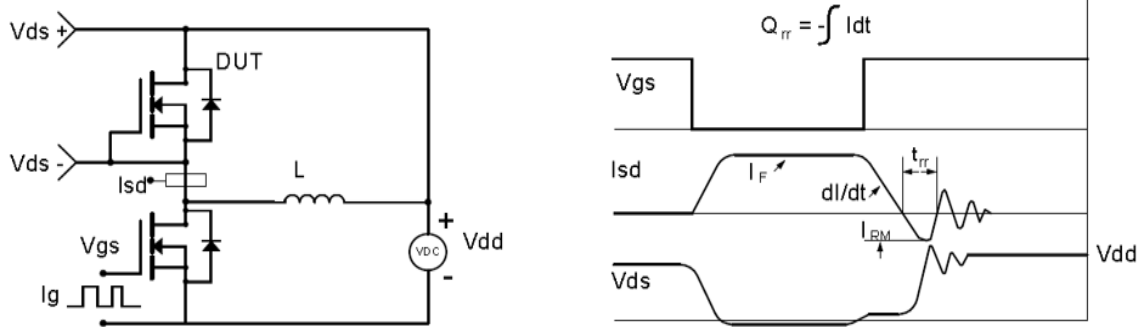


E_{AS} Test Circuit & Waveform



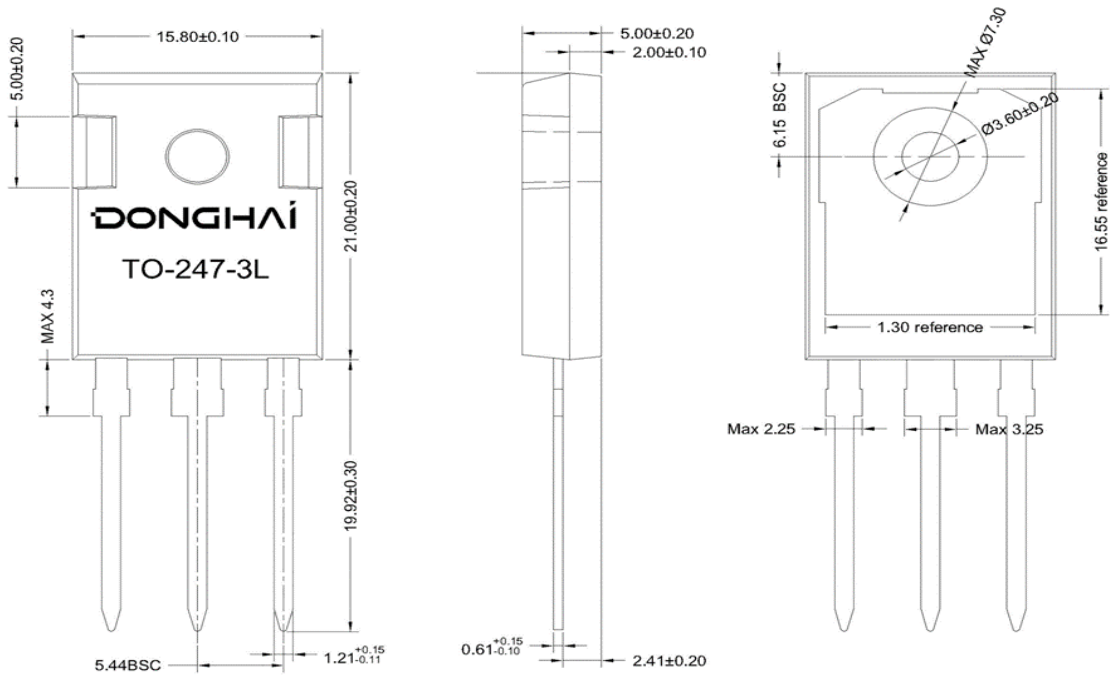
Test Circuit & Waveform

Diode Recovery Test Circuit & Waveform



Package Outline : TO-247-3L

*Dimensions in mm



Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as aviation, aerospace, life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are responsible for providing adequate safe measures when design their systems.

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